



Description

JMG N-channel Enhancement Mode Power MOSFET

Features

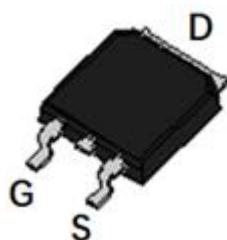
- 100V,10A
- $R_{DS(ON)} < 151\text{m}\Omega$ @ $V_{GS} = 10\text{V}$
- $R_{DS(ON)} < 190\text{m}\Omega$ @ $V_{GS} = 4.5\text{V}$
- Advanced Split Gate Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead free product is acquired

Application

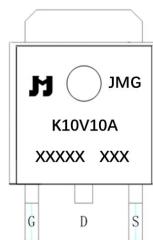
- Load Switch
- PWM Application
- Power management



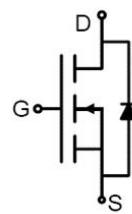
100% UIS TESTED!
100% ΔV_{ds} TESTED!



TO-252-3L(DPAK) top view



Marking and pin Assignment



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
JMGK10V10A	JMGK10V10A	TAPING	TO-252-3L	13inch	2500	25000

Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		100	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current		10	A
	$T_c = 100^\circ\text{C}$	6.5	A	
I_{DM}	Pulsed Drain Current ^{note1}		40	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		1.6	mJ
P_D	Power Dissipation	$T_c = 25^\circ\text{C}$	32	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		3.9	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +175	$^\circ\text{C}$

**Electrical Characteristics** ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.7	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}, I_D=5\text{A}$	-	116	151	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$	-	136	190	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=50\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$	-	154	-	pF
C_{oss}	Output Capacitance		-	34	-	pF
C_{rss}	Reverse Transfer Capacitance		-	6	-	pF
Q_g	Total Gate Charge	$V_{DS}=50\text{V}, I_D=5\text{A}, V_{GS}=10\text{V}$	-	4.3	-	nC
Q_{gs}	Gate-Source Charge		-	1.5	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	1.1	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=50\text{V}, I_D=5\text{A}, R_{GEN}=2\Omega, V_{GS}=10\text{V}$	-	14.7	-	ns
t_r	Turn-on Rise Time		-	3.5	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	20.9	-	ns
t_f	Turn-off Fall Time		-	2.7	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	10	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	40	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}, I_S=10\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	32	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	39	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J=25^\circ\text{C}, VDD=50\text{V}, VGS=10\text{V}, RG=25\Omega, L=0.5\text{mH}, I_{AS}=2.5\text{A}$

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

Typical Performance Characteristics

Figure 1: Output Characteristics

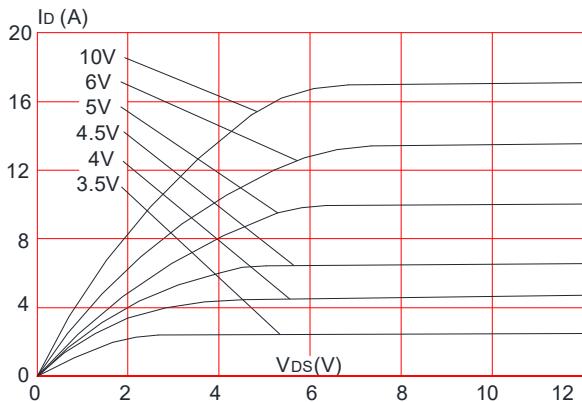


Figure 3: On-resistance vs. Drain Current

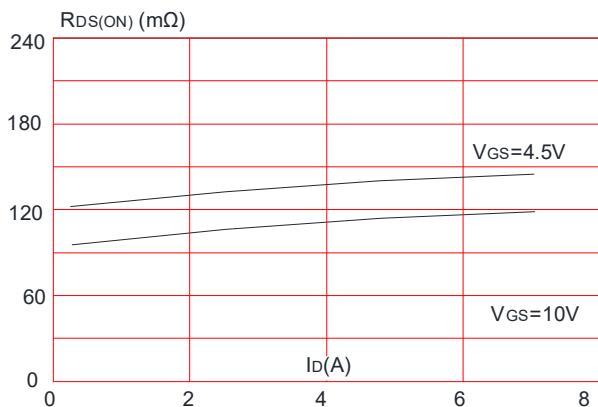


Figure 5: Gate Charge Characteristics

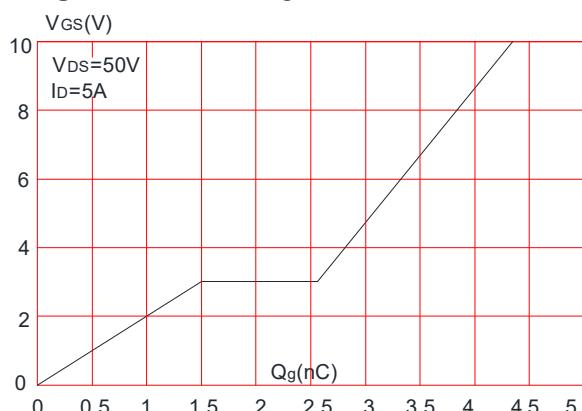


Figure 2: Typical Transfer Characteristics

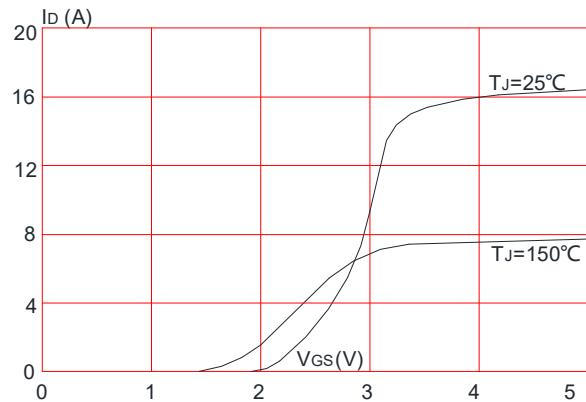


Figure 4: Body Diode Characteristics

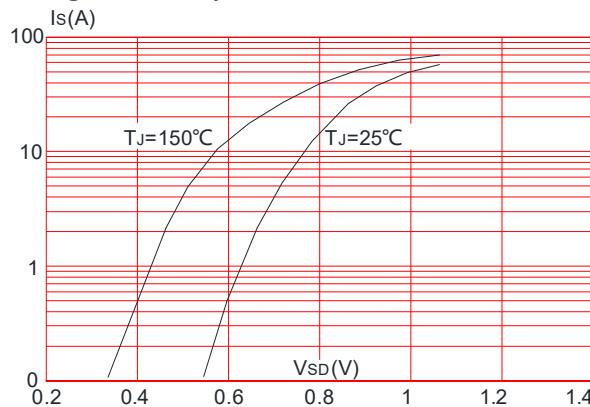


Figure 6: Capacitance Characteristics

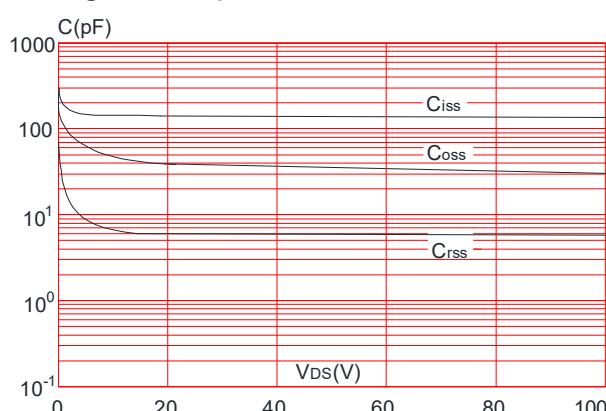


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

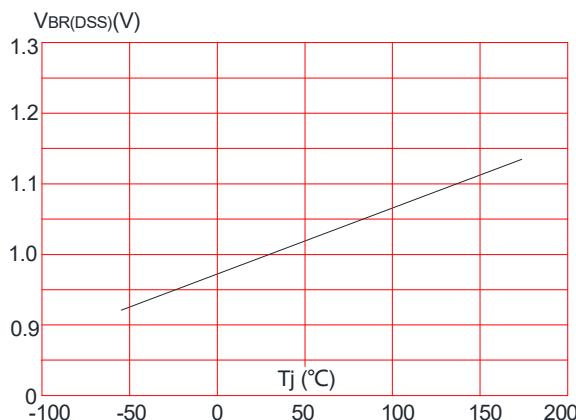


Figure 8: Normalized on Resistance vs. Junction Temperature

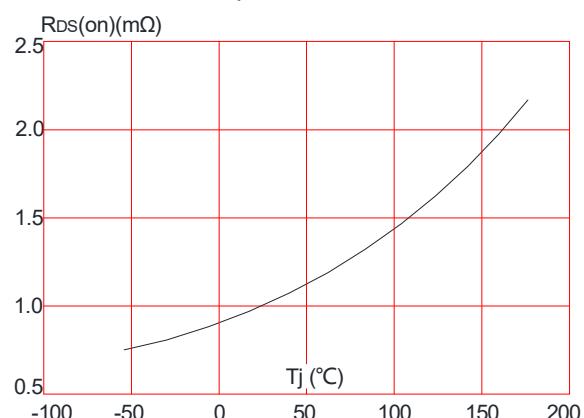


Figure 9: Maximum Safe Operating Area

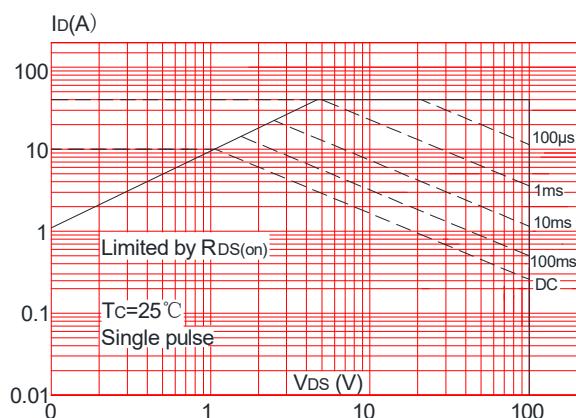


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

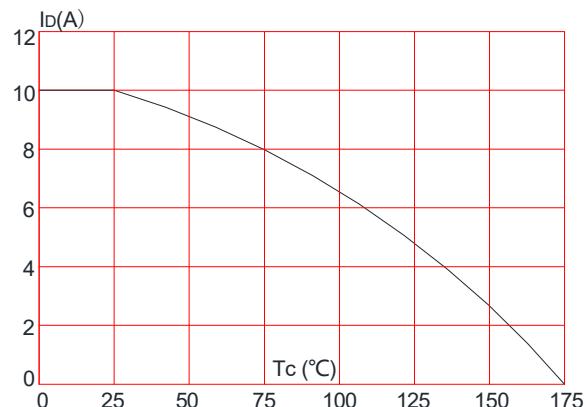
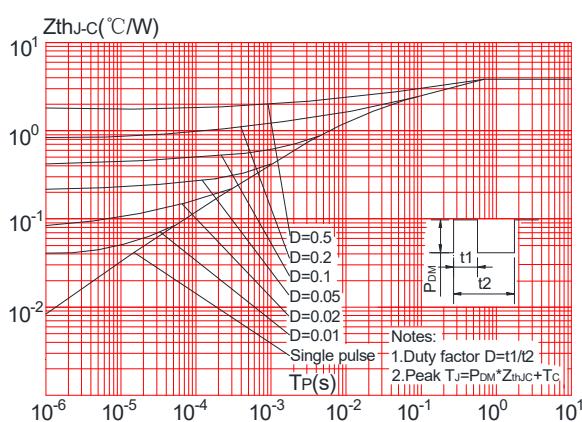


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



Test Circuit

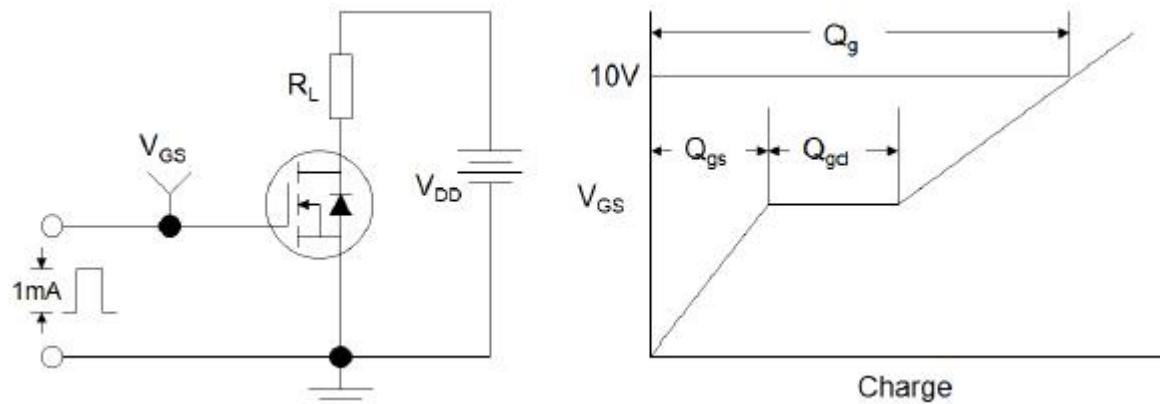


Figure1:Gate Charge Test Circuit & Waveform

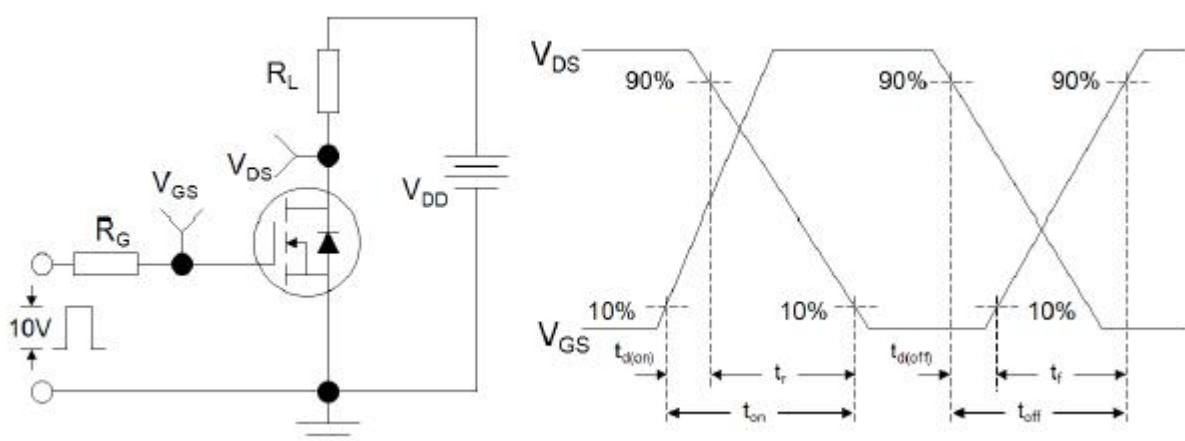


Figure 2: Resistive Switching Test Circuit & Waveforms

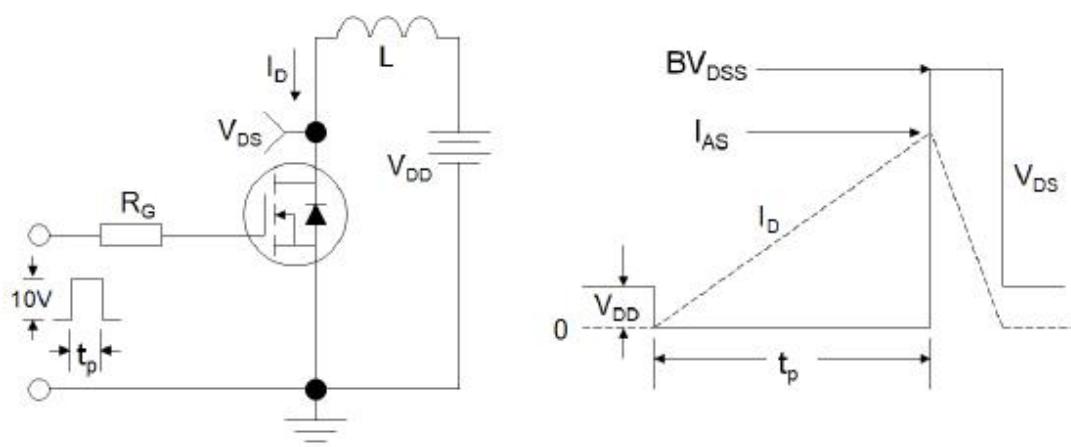
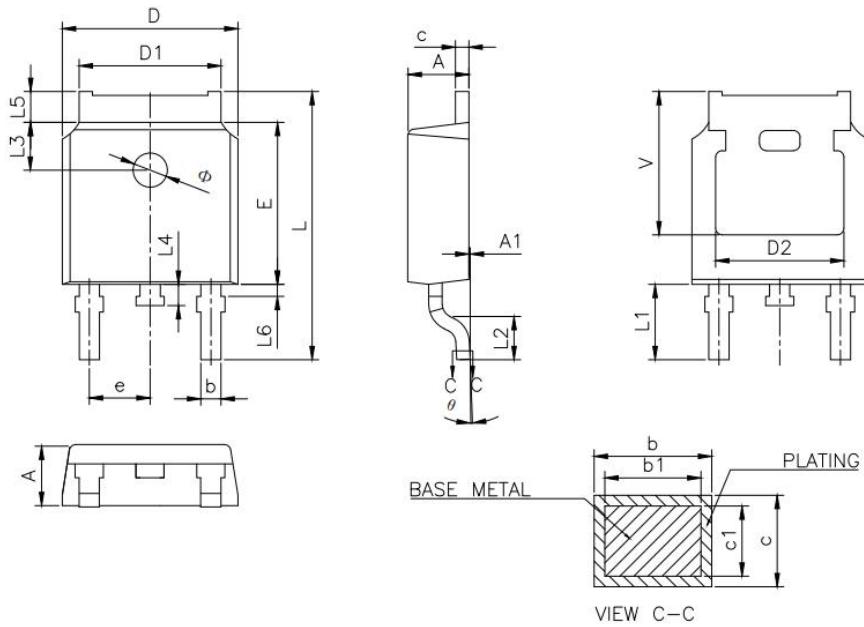


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



Package Mechanical Data-TO-252-3L



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	2.20	2.30	2.40
A1	0.00	--	0.127
b	0.66	0.76	0.86
c	0.46	0.51	0.58
D	6.50	6.60	6.70
D1	5.10	5.33	5.46
c1	0.46	0.51	0.56
c2	0.47	--	0.60
D2	4.83	REF.	
E	6.00	6.10	6.20
e	2.186	2.286	2.386
L	9.80	10.10	10.40
L1	2.90	REF.	
L2	1.40	1.50	1.60
L3	1.80	REF.	
L4	0.60	0.80	1.00
L5	0.90	--	1.25
L6	0.15	--	0.75
Φ	1.10	--	1.30
θ	0°	--	8°
V	5.35	REF	

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